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			L	U.S. PATEN	T DOCUMENTS			
EXAMINER	Cite		<u> </u>	,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,	Publication Date	Name of Patentee or Applicant		
INITIAL*	No.1		Document N	Number	MM-DD-YYYY	of Cited Document		
			Number-Kind C	ode ² (if known)	+			
KM			,783,882 B2		08/31/2004	Jeffrey A. Schmidt		
			,660,363 B1	<u> </u>	12/09/2003	Wilhelm Barthlott		
		US-6	,623,882 B2		09/23/2003	Jefferson Yang		
		US-6	,605,379 B1		08/12/2003	Robert Angelo Mercuri et al.		
		US-6	,541,389 B1		04/01/2003	Akira Kubo et al.		
		US-6	,530,554 B2		03/11/2003	Katsuhide Shimmo et al.		
·		US-6	,518,168 B1		02/11/2003	Paul G. Clem et al.		
		US-6	,455,021 B1		09/24/2002	Yahachi Saito		
	US-6,444,254 B1				09/03/2002	Ashutosh Chilkoti et al.		
		US-6	,432,866 B1		08/13/2002	Howard Tennent et al.		
		US-6	,423,372 B1		07/23/2002	Jan Genzer et al.		
			,403,388 B1		07/11/2002	Jeffrey D. Birdsley et al.		
			,312,303 B1		11/06/2001	Zvi Yaniv et al.		
			,299,981 B1		10/09/2001	Marie-Jose Azzopardi et al.		
			,900,160		05/04/1999	George M. Whitesides et al.		
			,725,788		03/10/1998	George N. Maracas et al.		
			,679,460		10/21/1997	Josephus M. Schakenraad et al.		
			,674,592		10/07/1997	John C. Clark et al.		
			,609,907		03/11/1997	Michael Natan		
			,252,835		10/12/1993	Charles M. Leiber et al.		
			,094,749		03/10/1992	Seita et al.		
			,909,989		03/20/1990	Fukazawa et al.		
			,753,712		08/21/1973	Janneck et al.		
			,724,673		04/03/1973	Ryon		
			002/0047822	A1	03/13/2003	Masahiro Hori et al.		
			002/0150684		10/17/2002	Ahalapitiya H. Jayatissa		
 		•	002/0136683		09/26/2002	Richard E. Smalley et al.		
			002/0122765		09/05/2002	Kazunaga Horiuchi et al.		
			002/0122709		08/22/2002	Christopher A. Bower et al.		
			002/0034879		03/21/2002	Wenbing Yun et al.		
$\vdash V \vdash$			002/0034879		03/21/2002	Yun Hi Lee et al.		
*		03-2	00210023314	A1	1 02/20/2002	I WI TI Lee et al.		

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include

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Sheet	2	of		7	Attome	y Docket Number	2267.962US0I			
			F(DREIGN PAT	ENT D	OCUMENTS				
EXAMINER INITIAL	Cite No. ¹	Foreign Patent Document Country Code ³ Number ⁴ Kind Code ⁵ (if known)				Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Té		
KM		WO 02/08			10/	24/2002	Ming-Hsien Wu et al.	—		
		WO 01/92	179 A1	 		06/2001	Karsten Reihs et al.	 		
		WO 01/94	034 A1		12/	13/2001	Dieter Scharnweber et al.			
		WO 00/39	368		07/	06/2000	Karsten Reihs et al.	1		
		WO 00/38	845		07/	06/2000	Karsten Reihs et al.			
		WO 01/79	142 A1		10/	25/2001	Peter Furniss et al.			
V		CA 23561	78 A1		07/	06/2000	Karsten Reihs et al.			
			NON P	ATENT LITE	ERATU	RE DOCUME	NTS			
EXAMINER INITIAL*	Cite No.1			, journal, serial, sy	/mposium		cle (when appropriate), title of the page(s), volume-issue number(s), lished	T²		
KM		DIDEM ÖNER et al., <u>Ultrahydrophobic Surfaces</u> . <u>Effects of Topography</u> <u>Length Scales on Wettability</u> , <i>Langmuir 2000</i> , June 23, 2000, vol. 16, no. 20, pp. 7777-7782								
		Measurem 1963, pp. 1	ents on 136-144	Rough Surfac	ces, Adı	ntact Angle Hysteresis II. Contact Angle s, Advances in Chemistry Series, March 22, y of Porous Surfaces, June 19, 1944, pp. 546-				
		551			-		· · · · · · · · · · · · · · · · · · ·			
						ol. 407, pp. 98	tion on sculpted solid			
	-		, The sp	preading of a			ce, J. Fluid Mech., 1983,	-1.		
		2001, vol.	17, pp.	6995-6998			Sessile Drops, Langmuir,			
		American . 55702/4	no. 5, pp. 55702/1-							
		S.G. MASON, Wetting and Spreading – Some Effects of Surface Roughness, Academic Press, 1978, pp. 321-326 H. KAMUSEWITZ et al., The relation between Young's equilibrium contact angle and the hysteresis on rough paraffin was surfaces, Elsevier Science B.V., 1999, pp. 271-279								
		Materials .	Science	, 1980, vol. 15	5, pp. 4.	31-437	surfaces, Journal of			
V							Assembly of 3-D Periodic			
EXAMINER SIGNATURE SIGNATURE STRUCTURES, Langmuir, 2002, vol. 18, pp. 5429-5437 CONSIDERED										

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. Applicant's unique citation designation number (optional). Applicant is to place a check mark here if English language Translation is attached.

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Sheet	3		of	7	Attorney Docket Number	2267.962US01				
			NON P	ATENT LITE	ERATURE DOCUME	ENTS				
EXAMINER INITIAL*	Cite No. ¹			, journal, serial, sy		, page(s), volume-issue number(s),	T²			
км		DARRON E. HILL et al., <u>Functionalization of Carbon Nanotubes with</u> <u>Polystyrene</u> , <u>Macromolecules</u> , 2002, vol. 35, pp. 9466-9471								
		ROBERT J. GOOD, A Thermodynamic Derivation of Wenzel's Modification of								
1			Young's Equation for Contact Angles; Together with a Theory of Hysteresis,							
		Journ	al of Americ	an Chemical	Society, October 20, 1	952, vol. 74, pp. 5041-				
		5042								
						wetting. I. Some effects of				
			ce roughness 954-1961	(theoretical),	Canadian Journal of	Chemistry, 1981, vol. 59,				
				Influence of S	Surface Roughness on	Wetting Dynamics				
				ol. 15, pp. 87	· · · - · · - · - · - · - · · · · · · ·	Trocking Dynamics,				
						Liquids on Finely-Grooved				
			J.F. OLIVER et al., The Apparent Contact Angle of Liquids on Finely-Grooved Solid Surfaces-A SEM Study, Gordon and Breach Science Publishers Ltd.,							
			1977, vol. 8, pp. 223-234							
		A.J.C	A.J.G. ALLAN et al., Wettability of Perfluorocarbon Polymer Films: Effect of							
		Roughness, Journal of Polymer Science, 1959, vol. XXXIX, pp. 1-8								
		J.B. S	J.B. SWEENEY et al., Equilibrium Thin Films on Rough Surfaces. 1. Capillary							
		and Disjoining Effects, Langmuir, 1993, vol. 9, pp. 1551-1555								
					hobic and Ultralyopho					
					<i>muir</i> , 1999, vol. 15, p					
					et al., <u>Ultrahyrophobi</u>					
					tion of Polypropylene					
			Poly(tetrafluoroethylene) Using Radio Frequency Plasma, Macromolecules,							
		1999, vol. 32, pp. 6800-6806 JOANNA AIZENBERG et al., Direct Fabrication of Large Micropatterned								
				-						
					l. 299, February 21, 20					
						Journal of Colloid and				
					975, vol. 53, no. 2, pp.	e Dependence of Contact				
						e Science, 1993, vol. 159,				
				our nut o	, conois una interjuc	Science, 1993, vol. 139,				
 			pp. 86-59 PETER S. SWAIN et al., Contact Angles on Heterogeneous Surfaces: A New							
		Look at Cassie's and Wenzel's Laws, Langmuir, 1998, vol. 14, pp. 6772-6780								
		KIYOHARU TADANAGA et al., Formation Process of Super-Water-Repellent								
					Transparency by the					
						997, vol. 80, no. 12, pp.	•			
V			-3216	· ,						
EXAMINER					DATE					
SIGNATURE					CONSIDERED					

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•			NON I	PATENT LIT	ERATURE DOCUM	ENTS				
EXAMINER INITIAL	Cite No. ¹									
KM 		with	KIYOHARU TADANAGA et al., Super-Water-Repellent Al ₂ O ₃ Coating Films with High Transparency, Communications of the American Ceramic Society, 1997, vol. 80, no. 4, pp. 1040-1042							
		Align	SHUHONG LI et al., Super-Hydrophobicity of Large-Area Honeycomb-Like Aligned Carbon Nanotubes, Journal of Physical Chemistry, 2002, vol. 106, no. 36, pp. 9274-9276							
		Elsev	vier Science	B. V., 2002, vo	l. 206, pp. 521-529	a-hydrophobic surfaces,				
		Quan	titive Asses	sment, Langm	uir, 2001, vol.17, pp.					
		14-15	5			News & Views, 2002, pp.				
			MASAHIDE TANIGUCHI et al., Correcting for Surface Roughness: Advancing and Receding Contact Angles, Langmuir, 2002, vol. 18, pp. 6465-6467							
		M. THIEME et al., Generation of Ultrahydrophobic Properties of Aluminuim – A First Step to Self-cleaning Transparently Coated Metal Surfaces, Advanced Engin. Mater., Internet, 2001, vol. 9, pp. 1								
		ZEN	YOSHIMIT	SU et al., Effe	ects of Surface Struct	ure on the Hydrophobicity 2002, vol. 18, 5818-5822				
		DAV p. 15		NE et al., Fluo	rsight, Brennan Rese	arch Group, January 2003,				
		349-3	359			f Different Roughness, pp.				
		Janua	ary 27, 1948	, pp. 11-16	es, Wool Industries R					
		EUN HEE CIRLIN et al., Roughness and Anisotropy Effects on wettability of Polytetrafluoreothylene and Sodium-treated Polytetrafluoroethylene, Journal of Polymer Science, 1973, vol. 11, pp. 785-799								
	,	PULP AND PAPER RESEARCH INSTITUTE OF CANADA, Liquid Spreading: Edge Effect for Zero Contact Angle, Journal of Colloid and Interface Science, August 1978, vol. 66, no. 1, pp. 200-202								
V		ROB	ERT N. WE	NZEL, Resist	ance of Solid Surface	s to Wetting by Water, vol. 28, no.8, pp. 988-994				
EXAMINER SIGNATURE					DATE CONSIDERED					

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EXAMINER INITIAL	Cite No.		Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published								
KM		WILL H. COGHILL et al., Why Water Over-Fills a Tumbler, Scientific American Supplement, July 27, 1918, vol. 86, no. 2221, pp. 52-53									
		R.D. SC surfaces	HULZE e	t al., <u>Young's</u> n empirical c	s equilibrium contact a						
		J.F. OLI	VER et al	., <u>An Experir</u>	nental Study of Some Is and Surfaces, 1980,	Effects of Solid Surface vol. 1, pp. 79-104					
		Містора	tterning o	n Flowerlike		n by the Sol-Gel Method,					
		S. HERI	MINGHA	US, Roughne		92 g, Europhysics Letters,					
		October 15, 2000, vol. 52, pp. 165-170 J. BICO et al., Rough wetting, Europhysics Letters, July 15, 2001 vol. 55, pp. 214-220 RANDY DOYLE HAZLETT, Fractal Applications: Wettability and Contact Angle, Journal of Colloid and Interface Science, July 1990, vol. 137, no. 2, 527-533									
		and Surf		nness, The Jo		between Contact Angle emistry, 1972, vol. 76, no.					
		J. KIJLS Colloids	TRA et a and Surfa	., Roughness aces, 2002, vo	ol. 206, pp. 521-529	-hydrophobic surfaces,					
		Fractal S	Structure,	J. Phys. Cher	m., 1996, vol. 100, pp.						
		220-226		- -		15, 1999, vol. 47, no. 2, pp.					
		H. YILDIRIM ERBIL et al., <u>Transformation of a Simple Plastic into a</u> <u>Superhydrophobic Surface</u> , <i>Science</i> , February 28, 2002, vol. 299, pp. 1377-1380									
	J.D. MILLER et al., Effect of Roughness as Determined by Atomic Force Microscopy on the Wetting Properties of PTFE Thin Films*, Polymer Engineering and Science, July 1996, vol. 36, no. 14, pp. 1849-1855										
V		ATSUSI	HI HOZU	MI et al., Pre	paration of ultra water CVD, Thin Solid Films	-repellent films by					
EXAMINER SIGNATURE					DATE CONSIDERED						

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. ¹Applicant's unique citation designation number (optional). ²Applicant is to place a check mark here if English language Translation is attached.

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EXAMINER INITIAL*	Cite No. ¹		Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published						
KM		on Li	BRIAN D. REISS et al., <u>DNA-Directed Assembly of Anisotropic Nanopaticles</u> on Lithographically Defined Surfaces and in Solution, Materials Research Society, 2001, vol. 635, pp.C6.2.1-C6.2.6						
		F.E. Angl	BARTELL et	al., Surface 1	Roughness as Relate	d to Hysteresis of Contact Chem., February 1953, vol.			
		F.E. Angle Paraf D. R.	BARTELL et es. II. The S fin-Glycerol- ICHARD et a	ystems Paraf Air ¹ . J. Phy l., Bouncing	fin-3 Molar Calcium s. Chem., April 1953	to Hysteresis of Contact Chloride Solution-Air and , vol. 57, pp. 455-463 ysics letters, June 15, 2000,			
		vol. 50, pp. 769-775 JUN YANG et al., Microfluid Flow in Circular Microchannel with Electrokinetic Effect and Navier's Slip Condition, Langmuir, 2003, vol. 19, no. 4, pp. 1047-1053							
		on Re	ough Surface	s, Langmuir,	2003, vol. 19, no. 4,				
		SUGURU OKUYAMA et al., <u>Periodic Submicrocylinder Diamond Surfaces</u> <u>Using Two-Dimensional Fine Particle Arrays</u> , <i>Langmuir</i> , 2002, vol. 18, no. 22, pp. 8282-8287							
		J. Ele	ectroanal. Ch	em., 1993, vo	l. 353, pp. 209-215	ions on organic electrodes.,			
		of Co	olloid and Inte	erface Science	e, June 1, 1977, vol.				
		Micro	oscopy. Silic	one Oil on Po	Contact Angles by Solished Aluminum, J 11, vol. 35, no. 2, pp.	ournal of Colloid and			
		NORMAN R. MORROW, The Effects of Surface Roughness on Contact Angle with Special Reference to Petroleum Recovery, The Journal of Canadian Petroleum, October-December 1975, pp. 42-54							
		411,	pp. 924-896			Scale Physical Parism			
		Lette	rs, February 2	24, 1997, vol.	78, no. 8, pp. 1520-				
V						hening of Polymers on Surfaces, 1984, pp.319-331			
EXAMINER DATE SIGNATURE CONSIDERED									

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. ¹Applicant's unique citation designation number (optional). ²Applicant is to place a check mark here if English language Translation is attached.

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Sheet	7		of	7	Attomey Docket Number 22	267.962US01				
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EXAMINER INITIAL	Cite No. ¹			, journal, serial, sy		e (when appropriate), title of the age(s), volume-issue number(s), hed	T ²			
KM			R. SHUTTLEWORTH et al., The Spreading of a Liquid Over a Rough Solid, February 23, 1948, pp. 16-22							
					o Spreading of Liquids Science, May 1977, vo	by Sharp Edges ¹ , ol. 59, no. 3, pp. 568-579				
					epellent Fractal Surface 996, vol. 12, no. 9, pp. 2					
	PHILLIP G. WAPNER et al., Partial Wetting Phenomena on Nonplanar Surfaces and in Shaped Microchannels, Langmuir, 2002, vol. 18, no. 4, pp. 1225-1230									
V		JOONWON KIM et al., Nanostructured Surfaces for Dramatic Reduction of Flow Resistance in Droplet-Based Microfluidics, 2002, pp. 479-482								
			· · · - · · · · · · · · · · · · · · · ·							
		<u> </u>								
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EXAMINER SIGNATURE		/Kri	shnan Menon/	(08/13/2006)	DATE					

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